

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10552837	BEYER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	CHUN CHEUNG	3728

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
206	321	3/5/2009	CC
428	43	3/6/2009	CC
206	83.5, 442, 216, 223	3/9/2009	CC
53	443, 447, 528	3/9/2009	CC
206	321	9/3/2009	CC
206	321	4/21/2010	CC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Plus Search	3/5/2009	CC
Inventor Search	3/5/2009	CC
East Search	3/5/2009	CC
Backward/Forward Search	3/5/2009	CC
Spoke to primary (Luan Bui) for search	3/6/2009	CC
Spoke with SPE (Mickey Yu)	9/3/2009	CC
East, classification and Word search	9/3/2009	CC
Additional East, classification and Word Search	4/22/2010	CC
Spoke with SPE (Mickey Yu)	4/20/2010	CC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/CHUN CHEUNG/  
Examiner Art Unit 3728